

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/784,165	KAMEI, CHIKASHI	
Examiner	Art Unit	
Ryan D. Walsh	2852	

	SEARCHED					
Class	Subclass	Date	Examiner			
399	33	7/15/2005	RDW			
399	67	7/15/2005	RDW			
399	69	7/15/2005	RDW			
399	70	7/15/2005	RDW			
399	96	7/15/2005	RDW			
399	328	7/15/2005	RDW			
399	330	7/15/2005	RDW			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARCI)
·	DATE	EXMR
East: See attached	7/15/2005	RDW
Consulted: Primary Examiner David Gray	7/15/2005	RDW